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Application/Control No.	Applicant(s)/Patent unde Reexamination	r
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Examiner	Art Unit	
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370	235	12/12/2007	sc			
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INTERFERENCE SEARCHED			
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SEARCH NOT (INCLUDING SEARCH		)
	DATE	EXMR
EAST Image and keyword search in USPAT, US-PGPUB, DERWENT, EPO, JPO, and IBM_TDB (see attached search startegy)	12/12/2007	sc
Inventor name and Assignee search in PALM EXPO and EAST	12/12/2007	sc